SEM 2016

October 25-27, 2016, Göteborg, SWEDEN

Tuesday October 25, 2016

08.45 - 09.00	***Registration: outside Kollektorn***
09.00 - 12.10	***LECTURE HALL Kollektorn***
09.00 - 09.20	Welcome address and introductory remarks by the organizers *Lena Falk and Mats Halvarsson, Physics, Chalmers*
09.20 - 09.55	Image formation in the scanning electron microscope *Mats Eriksson, Spectral Solutions, Sweden*
09.55 - 10.25	**COFFEE in the Canyon**
10.25 - 11.00	Detectors for secondary and backscattered electrons *Herbert Pavlicek, Zeiss, Germany*
11.00 - 11.35	Principles of X-ray microanalysis *Igor Nemeth, Bruker Nano GmbH, Germany*
11.35 - 12.10	Introduction to variable pressure SEM *Bradley Thiel, SUNY Polytechnic Institute, USA*
12.10 - 13.00	**LUNCH in the Canyon**
13.00 - 19.00	***PRACTICALS***
13.00 - 14.15	Demonstrations -- Session I
14.15 - 14.45	**COFFEE in the Canyon**
14.45 - 17.15	Demonstrations -- Session II
17.15 - 19.00	Open Lab
19.15	**COURSE DINNER**

Wednesday October 26, 2016

09.00 - 12.00 *LECTURE HALL KOLLEKTORN*

09.00 - 09.10 Introductory remarks by the organizers

09.10 - 09.45 Probe formation in the scanning electron microscope
Mats Eriksson, Spectral Solutions, Sweden

09.45 - 10.15 **COFFEE in the Canyon**

10.15 - 10.50 Poor conductors - The art of collecting electrons under adverse condition
Leon Hütsch, Jeol (Germany) GmbH

10.50 - 11.15 X-ray spectral measurement
Håkan Vikström, Oxford Instruments Nordiska AB

11.15 - 11.30 **BREAK**

11.30 - 12.00 Quantitative X-ray analysis I: Basic procedures
Håkan Vikström, Oxford Instruments Nordiska AB

12.00 - 13.00 **LUNCH in the Canyon**

13.00 - 20.00 ***PRACTICALS***

13.00 - 14.15 Demonstrations -- Session III

14.15 - 14.45 **COFFEE in the Canyon**

14.45 - 17.15 Demonstrations -- Session IV

17.15 **SANDWICHES and REFRESHMENTS**

17.15 - 20.30 Open Lab

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Thursday October 27, 2016

09.00 - 12.00	***LECTURE HALL KOLLEKTORN***
09.00 - 09.05	Introductory remarks by the organizers
09.05 - 09.35	Quantitative X-ray analysis II: Standardless analysis *Igor Nemeth, Bruker Nano GmbH, Germany*
09.35 - 10.05	Microanalysis and applications in variable pressure SEM *Bradley Thiel, SUNY Polytechnic Institute, USA*
10.05 - 10.30	**COFFEE in the CANYON**
10.30 - 11.00	DualBeams and 3D applications *Ellen Baken, FEI Company, The Netherlands*
11.00 - 11.30	Integrated TOF-SIMS as enhanced analytical potential of FIB-SEM *Vitezslav Ambroz, TESCAN ORSAY HOLDING a.s., Czech Republic*
11.30 - 11.50	Multibeam scanning electron microscopes and miniature columns *Bradley Thiel, SUNY Polytechnic Institute, USA*
11.50 - 12.00	Concluding remarks by the organizers
12.00 - 12.45	**LUNCH in the CANYON**
12.45 - 15.30	***PRACTICALS***
12.45 - 14.00	Demonstrations -- Session V
14.00 - 14.15	**COFFEE in the CANYON**
14.15 - 15.30	Demonstrations -- Session VI
15.30	***End of Course***